

<b>Notice of References Cited</b>	Application/Control No. 10/572,515	Applicant(s)/Patent Under Reexamination HOYANO ET AL.	
	Examiner BONG-SOOK BAEK	Art Unit 4161	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,541,488 b1	04-2003	Bernat et al.	514/327
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO/2002/028827	11-2002	PCT	Okazaki et al.	
	O					
	P					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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